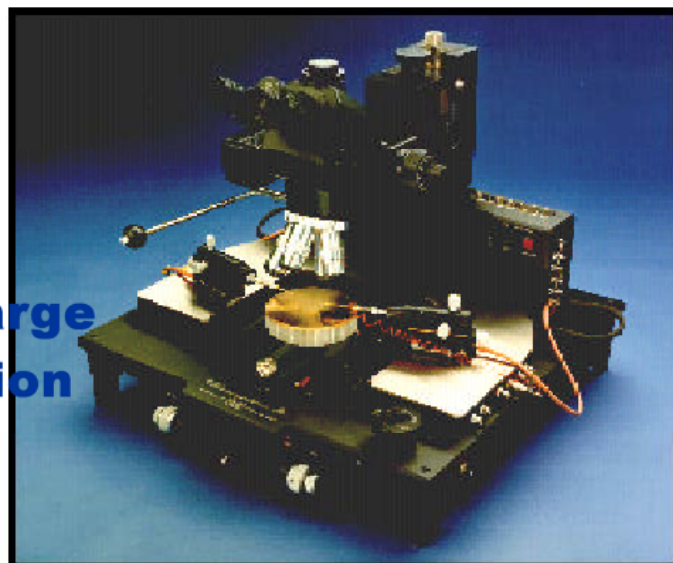


Models 6150/6200

Probing Stations

Models 6150 and 6200 probing stations provide submicron probing capability in a lower cost station. The high resolution stage with fast pullout provides the precision needed for engineering analysis and the efficient utility needed for production testing.



The complete document is too large for efficient web site transmission and must be ordered from Micromanipulator

Our Features:

Massive machined, anodized structure fully braced for rigidity.

Linear platen lift with three locking "up" positions.

Microscope lift delay.

Platen fine lift.

Fast microscope lift with lock; standard on the 6200, optional on the 6150.

Gold plated vacuum chuck (stainless steel optional).

360° chuck Theta rotation with coarse and fine control in both the 6200 and the 6150.

Microscope mount, vacuum valves, and BNC connector manifold standard.

Permanently planarized stage and vacuum chuck.

Your Benefits:

Maximizes rigidity and minimizes vibration.

Lifts probes quickly in planar fashion for sample or location changes.

Set microscope to lift with platen after probes leave sample but before they hit microscope objectives.

Allows submicron adjustment of probe or probe card vertical position.

Allows microscope to be cleared from probe area without disturbing probes.

Maximizes electrical contact to chuck surface.

Allows positioning of sample to stage X-Y or probe card.

All necessary hardware for clean, ready to use station is provided.

Minimizes set-up time.



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